

Emittance Measurement by Single Slit Scanning for the SRF Gun at HZDR

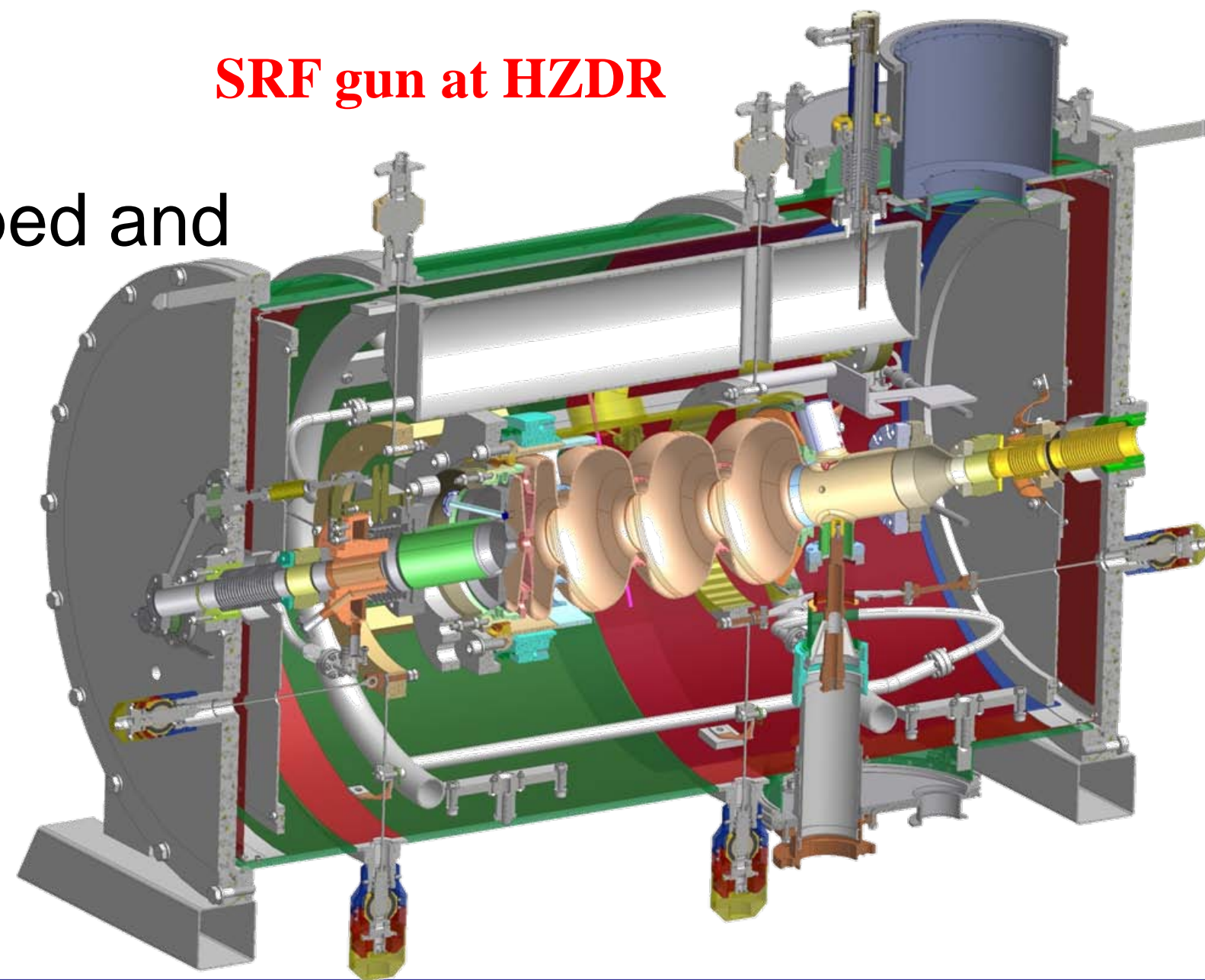


P. Lu, A. Arnold, P. Murcek, J. Teichert, H. Vennekate, R. Xiang



Background

- a 3½-cell SRF gun was developed and commissioned at HZDR
- the SRF gun needs further optimization and refinement
- solenoid scanning emittance measurement performed, detailed phase space needed

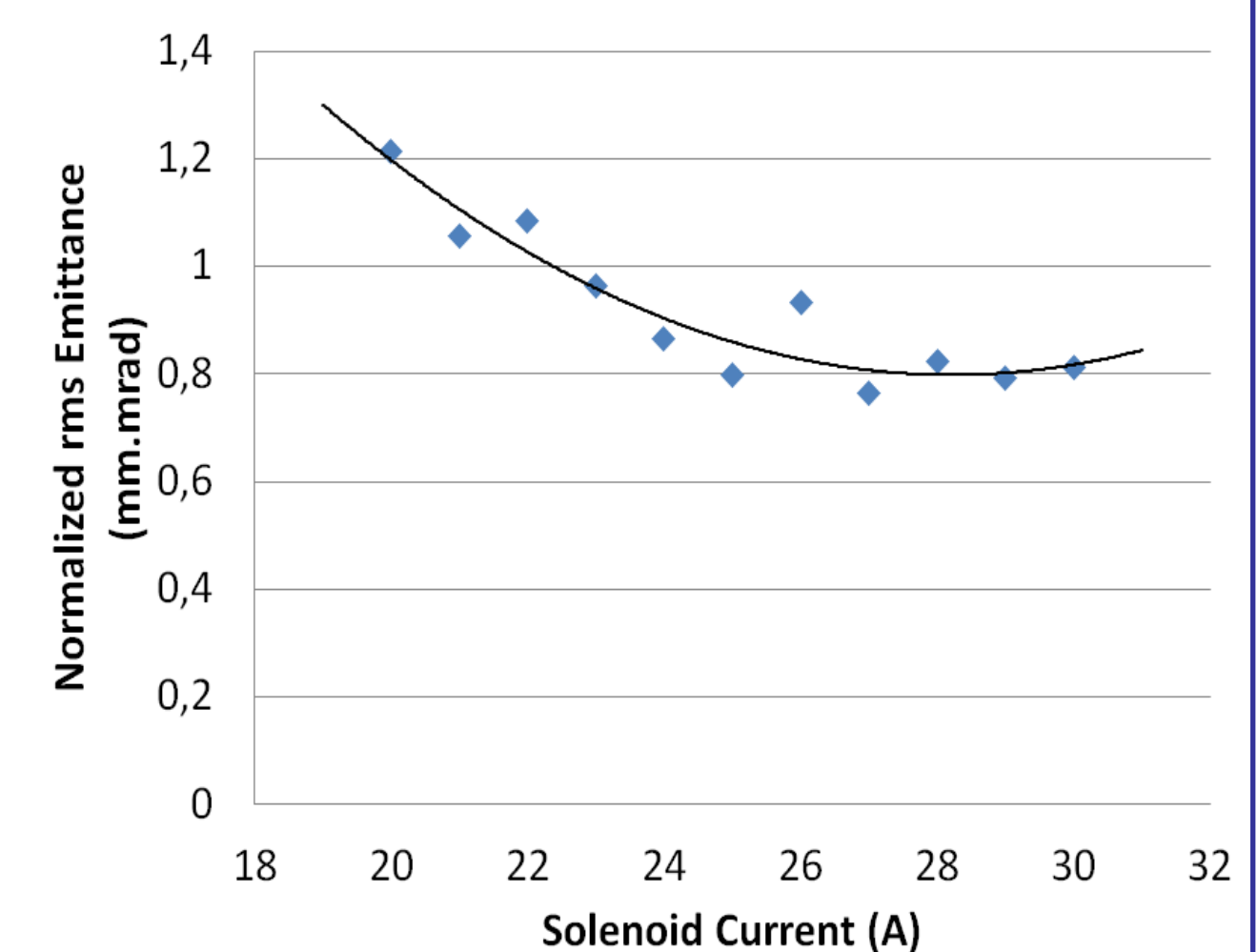
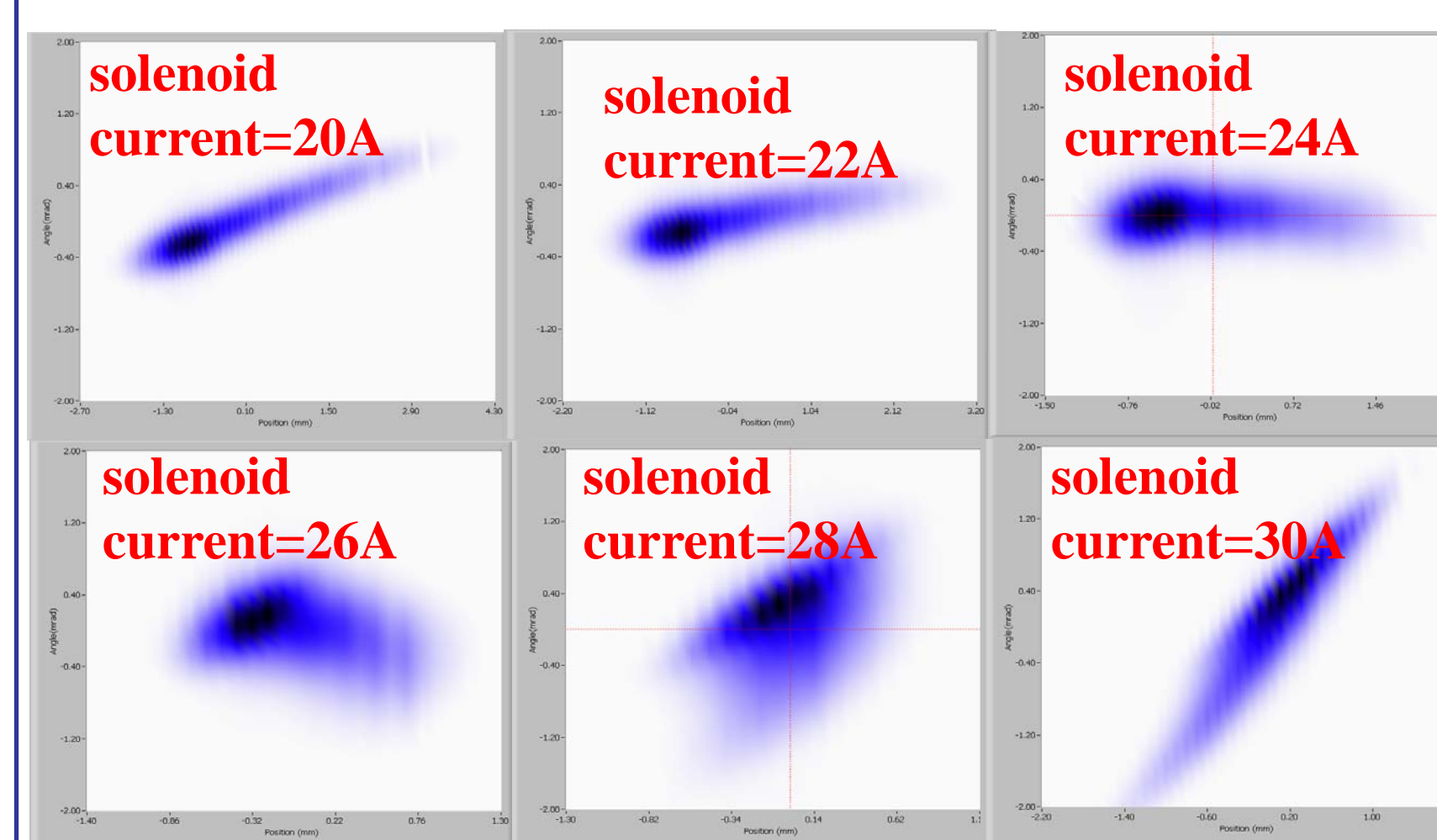


Preliminary Measurements

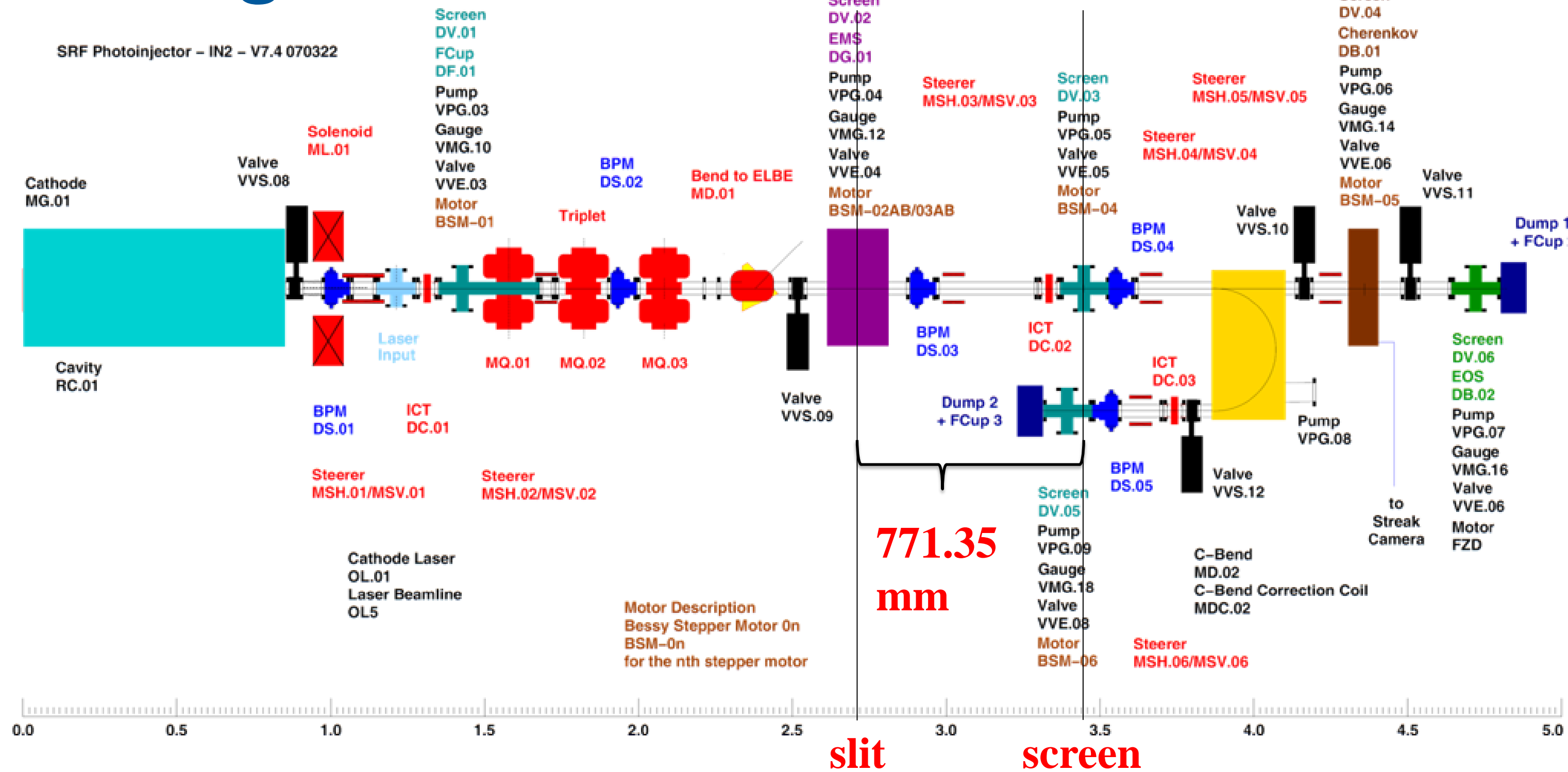
As a commissioning of the whole setup and software, we did 3 measurements of the SRF gun emittance with a change in the solenoid current, laser phase (compared to RF phase) and DC voltage on the cathode. The electron beam energy is 2.2 MeV. The bunch charge is about 0.05 pC. For the emittance values listed below, we will do further error analysis.

Emittance vs. Solenoid current:

- solenoid current scanned: from 20 A to 30 A
- laser phase: 30°
- DC voltage: 5 kV
- bunch charge: 0.05 pC

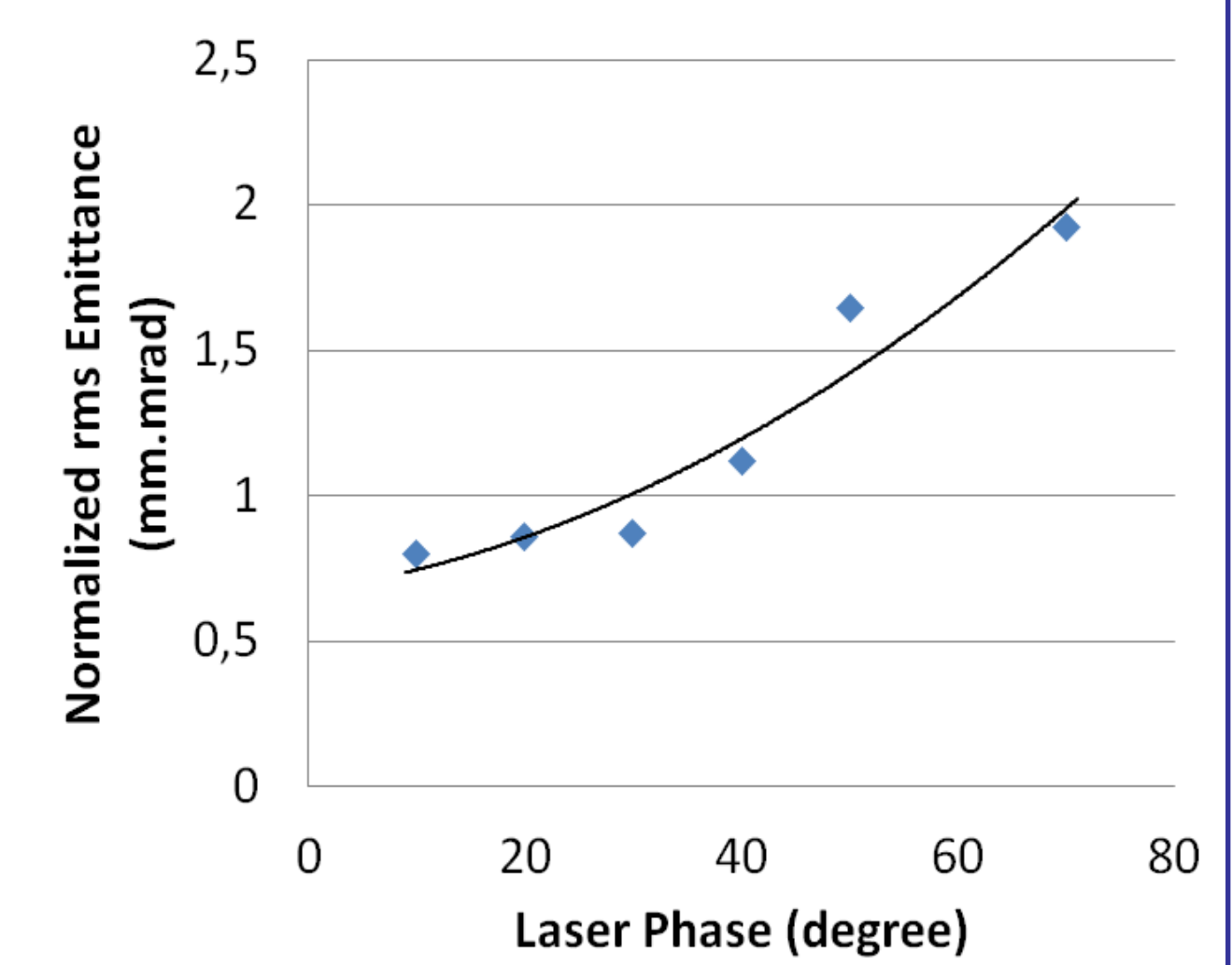
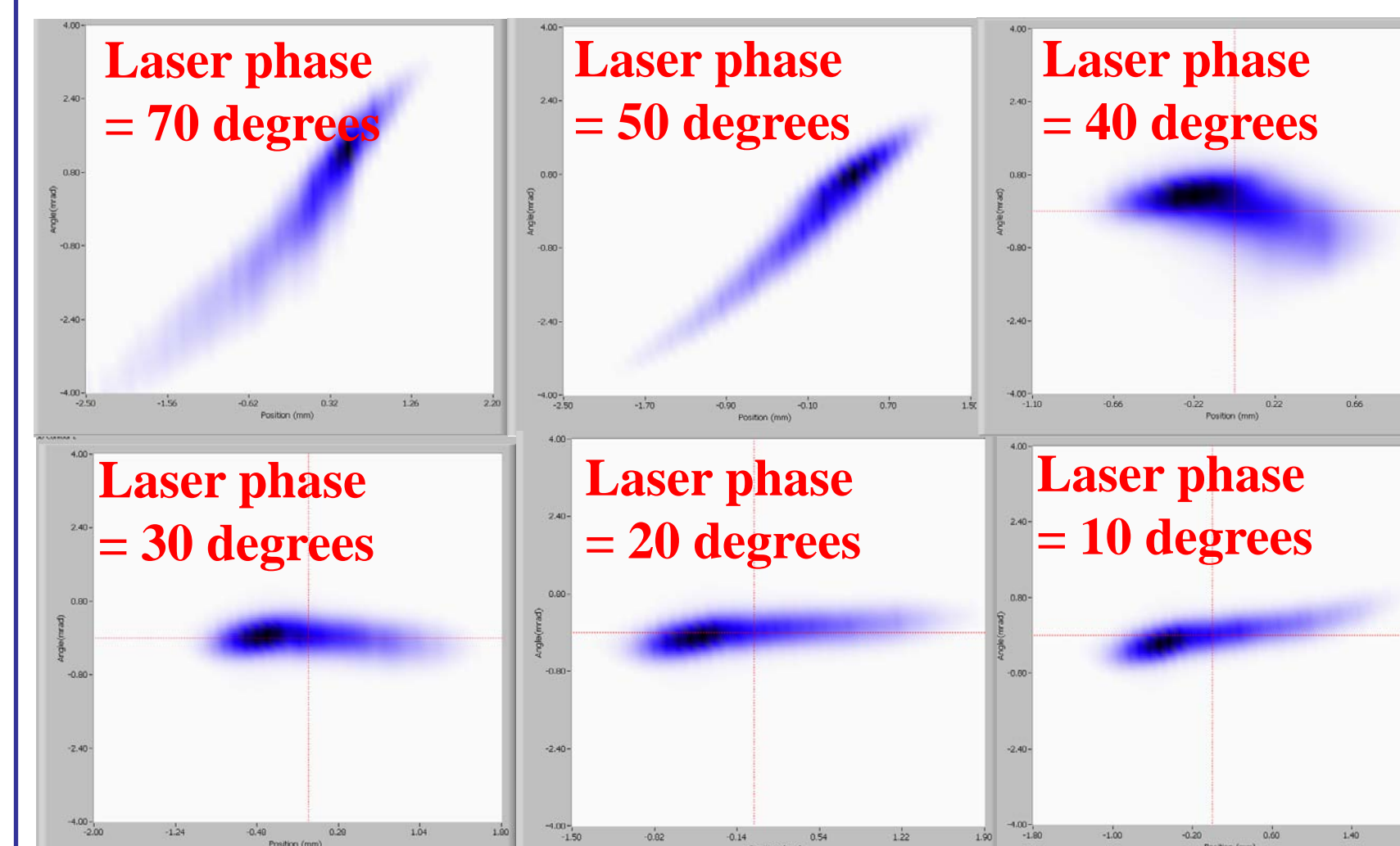


Diagnostics Beam Line



Emittance vs. Laser phase:

- laser phase scanned: from 10° to 70°
- solenoid current: 25 A
- DC voltage: 5 kV
- bunch charge: from 0.042 pC to 0.052 pC



Single-slit Scanning

Layout:

- tungsten slit board at section x
- YAG screen at section X
- camera shielded by lead

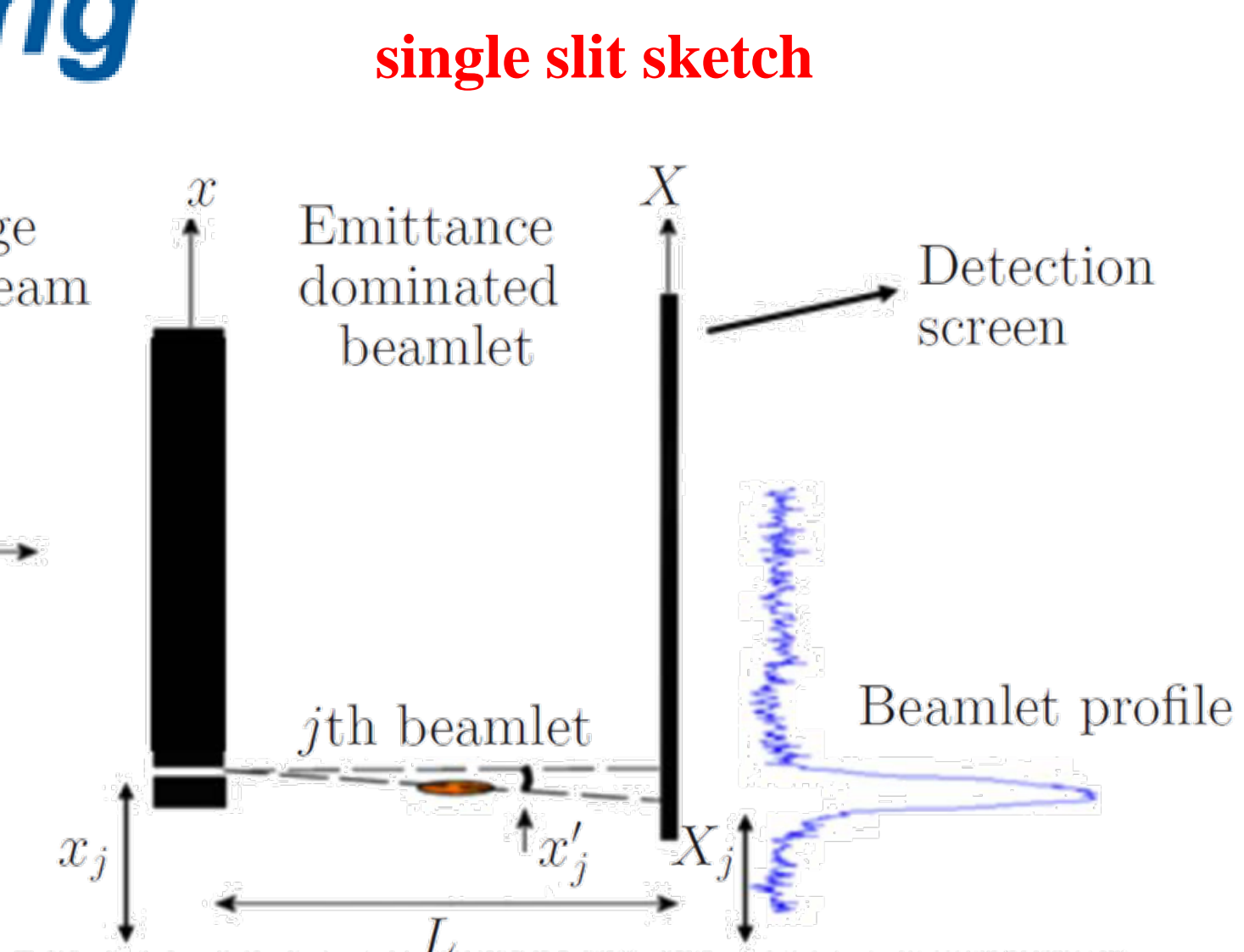
$$\epsilon_{n,rms} = \beta\gamma\sqrt{\langle x^2 \rangle \langle x'^2 \rangle - \langle x \cdot x' \rangle^2}$$

Advantages:

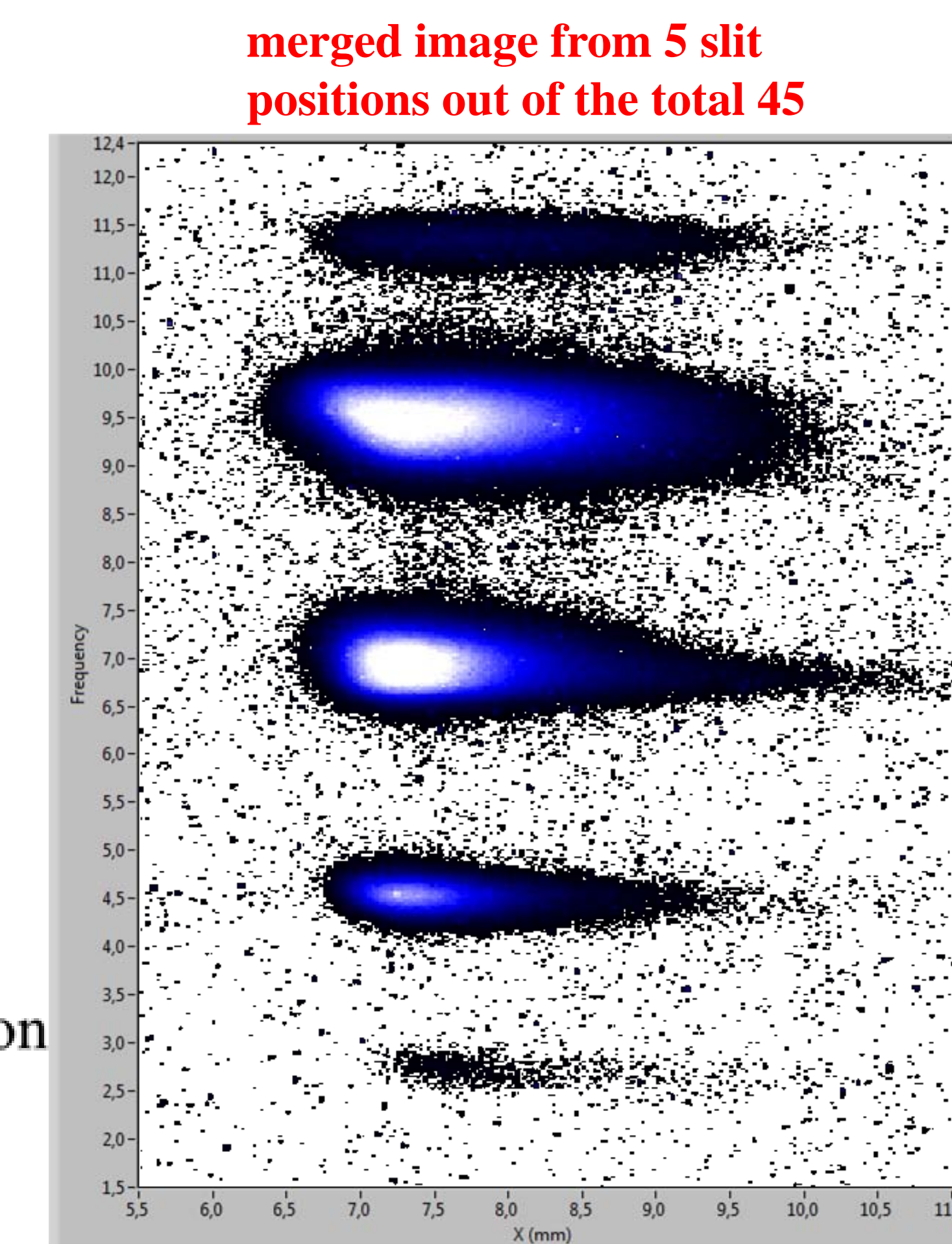
- space charge influence weakened
- data overlap avoided
- high resolution of phase space

Mesurement steps:

- record beam parameters and scanning parameters in a "ini file"
- record background data
- scan the slit and record n images at each position
- eliminate the background and noises, fix errors known
- get the "beamlet profile" by integration
- calculate the rms emittance $\epsilon_{n,rms}$

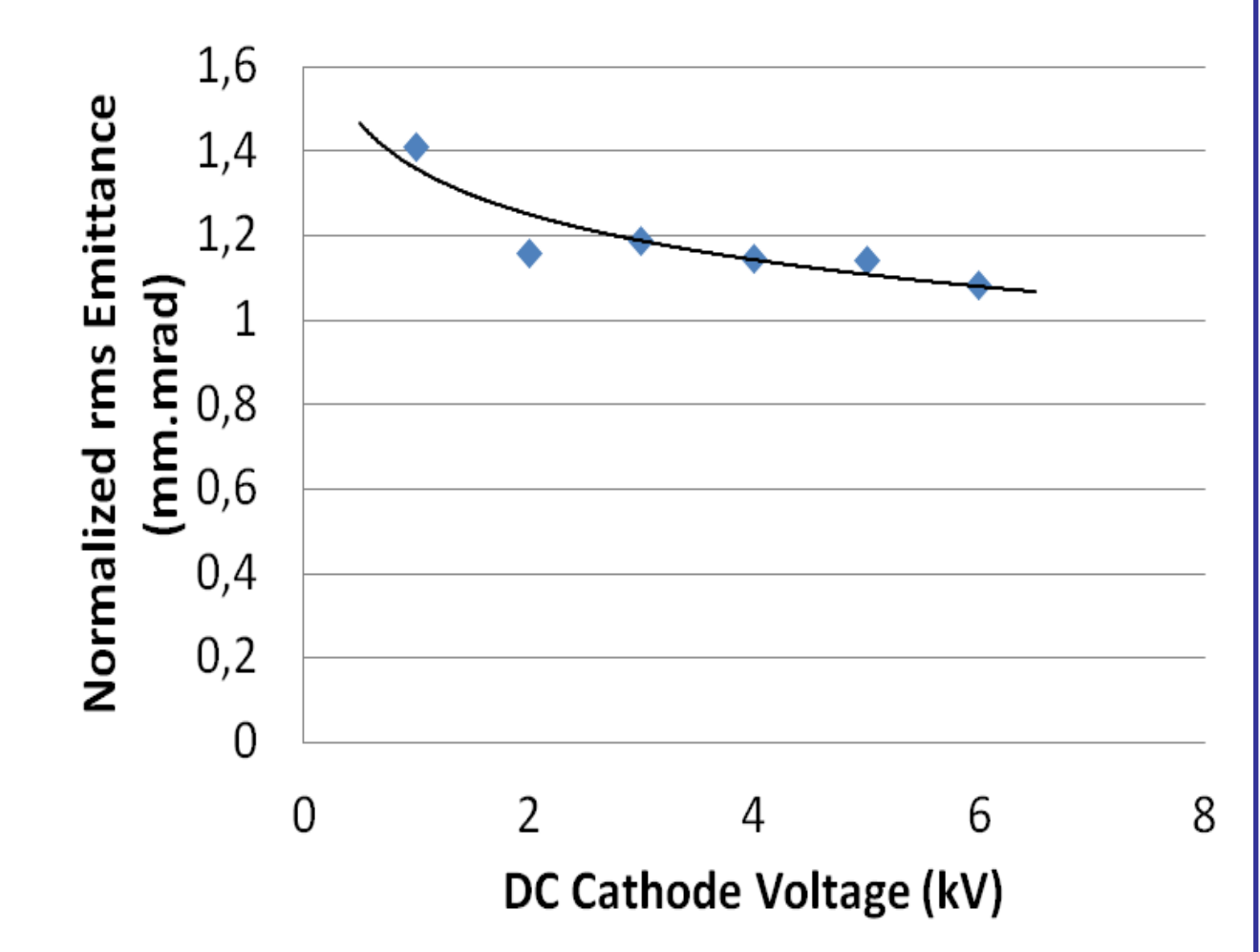
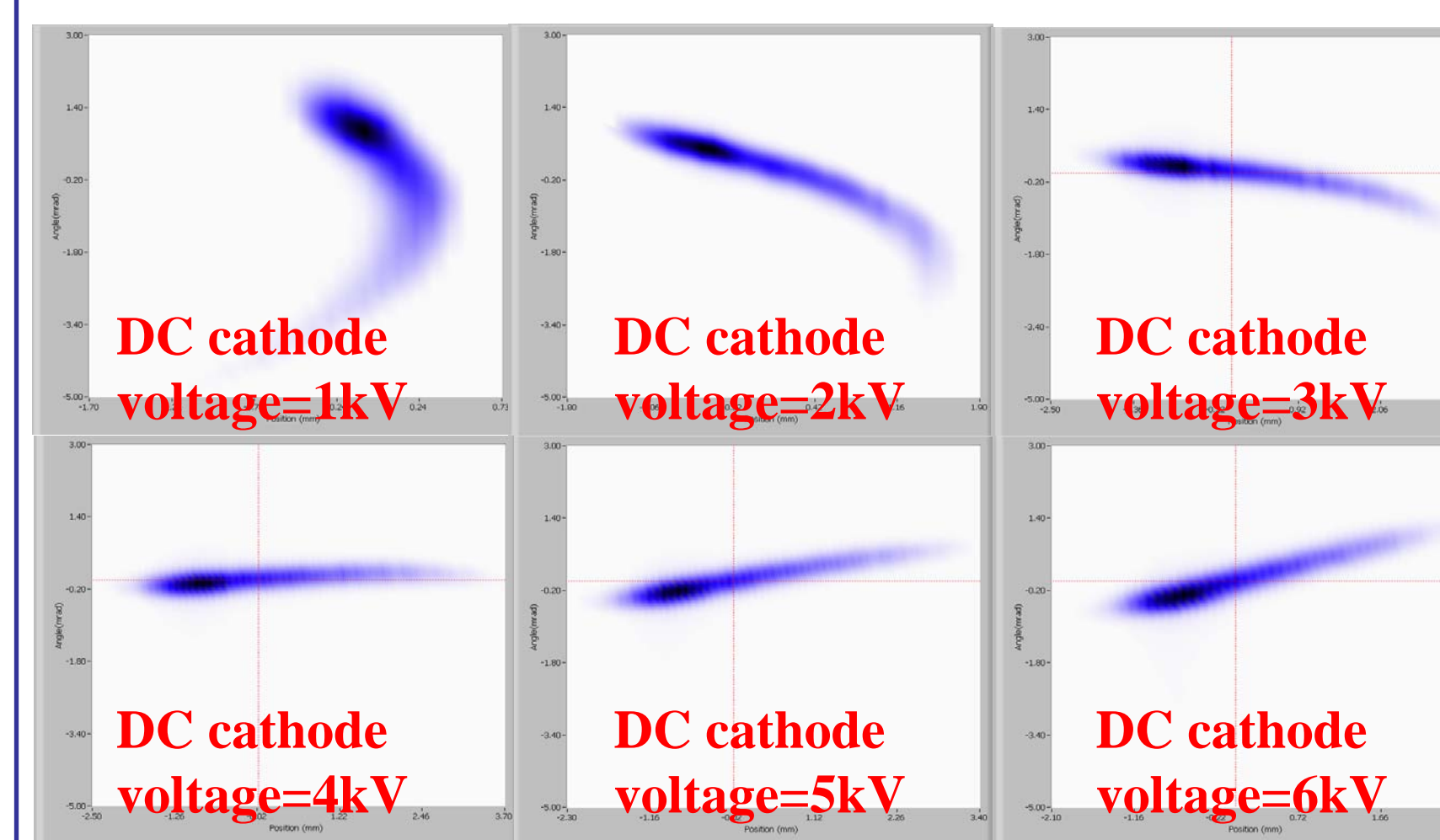


L	Slit width	Thick-ness	Pixels
771.35 mm	0.1 mm	1.5 mm	660x495



Emittance vs. DC voltage:

- DC Voltage scanned: from 1 kV to 6 kV
- solenoid current: 21 A
- laser phase: 30°
- bunch charge: from 0.046 pC to 0.053 pC



Work in Schedule

- optimization of the algorithm
- comparison with simulations
- check with solenoid scanning method
- analysis of errors

Acknowledgments

We acknowledge the support of the European Community-Research Infrastructure Activity under the FP7 programme (EuCARD, contract number 227579), as well as the support of the German Federal Ministry of Education and Research grant 05 ES4BR1/8, and the LA³NET funding from the European Commission under Grant Agreement Number GA-ITN-2011-289191.